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Details

Product Status	Obsolete
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I ² S, POR, PWM, WDT
Number of I/O	11
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 11x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	16-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-16-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1301t016f0016aaxuma1

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Table of Contents

1	Summary of Features	8
1.1	Ordering Information	10
1.2	Device Types	10
1.3	Device Type Features	11
1.4	Chip Identification Number	12
2	General Device Information	15
2.1	Logic Symbols	15
2.2	Pin Configuration and Definition	17
2.2.1	Package Pin Summary	20
2.2.2	Port I/O Functions	23
3	Electrical Parameter	26
3.1	General Parameters	26
3.1.1	Parameter Interpretation	26
3.1.2	Absolute Maximum Ratings	27
3.1.3	Operating Conditions	28
3.2	DC Parameters	29
3.2.1	Input/Output Characteristics	29
3.2.2	Analog to Digital Converters (ADC)	32
3.2.3	Out of Range Comparator (ORC) Characteristics	36
3.2.4	Analog Comparator Characteristics	37
3.2.5	Temperature Sensor Characteristics	38
3.2.6	Power Supply Current	39
3.2.7	Flash Memory Parameters	41
3.3	AC Parameters	42
3.3.1	Testing Waveforms	42
3.3.2	Output Rise/Fall Times	43
3.3.3	Power-Up and Supply Threshold Characteristics	44
3.3.4	On-Chip Oscillator Characteristics	46
3.3.5	Serial Wire Debug Port (SW-DP) Timing	48
3.3.6	SPD Timing Requirements	49
3.3.7	Peripheral Timings	50
3.3.7.1	Synchronous Serial Interface (USIC SSC) Timing	50
3.3.7.2	Inter-IC (IIC) Interface Timing	53
3.3.7.3	Inter-IC Sound (IIS) Interface Timing	55
4	Package and Reliability	57
4.1	Package Parameters	57
4.1.1	Thermal Considerations	57
4.2	Package Outlines	59

Table 4 XMC1300 Chip Identification Number

Derivative	Value	Marking
XMC1301-T016F0008	00013032 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-T016F0016	00013032 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1301-T016X0008	00013033 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-T016X0016	00013033 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-T016X0008	00013033 01FF00FF 00001FF7 0000900F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1302-T016X0016	00013033 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-T016X0032	00013033 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1301-T038F0008	00013012 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-T038F0016	00013012 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1301-T038F0032	00013012 01CF00FF 00001FF7 0000100F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-T038X0016	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-T038X0032	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-T038X0064	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00011000 101ED083 _H	AA
XMC1302-T038X0128	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00021000 101ED083 _H	AA
XMC1302-T038X0200	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00033000 101ED083 _H	AA
XMC1301-Q024F0008	00013062 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-Q024F0016	00013062 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA

Summary of Features
Table 4 XMC1300 Chip Identification Number (cont'd)

Derivative	Value	Marking
XMC1302-Q024F0016	00013062 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-Q024F0032	00013062 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-Q024F0064	00013062 01FF00FF 00001FF7 0000900F 00000B00 00001000 00011000 101ED083 _H	AA
XMC1302-Q024X0016	00013063 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-Q024X0032	00013063 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-Q024X0064	00013063 01FF00FF 00001FF7 0000900F 00000B00 00001000 00011000 101ED083 _H	AA
XMC1301-Q040F0008	00013042 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-Q040F0016	00013042 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1301-Q040F0032	00013042 01CF00FF 00001FF7 0000100F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-Q040X0016	00013043 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-Q040X0032	00013043 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-Q040X0064	00013043 01FF00FF 00001FF7 0000900F 00000B00 00001000 00011000 101ED083 _H	AA
XMC1302-Q040X0128	00013043 01FF00FF 00001FF7 0000900F 00000B00 00001000 00021000 101ED083 _H	AA

2.2 Pin Configuration and Definition

The following figures summarize all pins, showing their locations on the different packages.

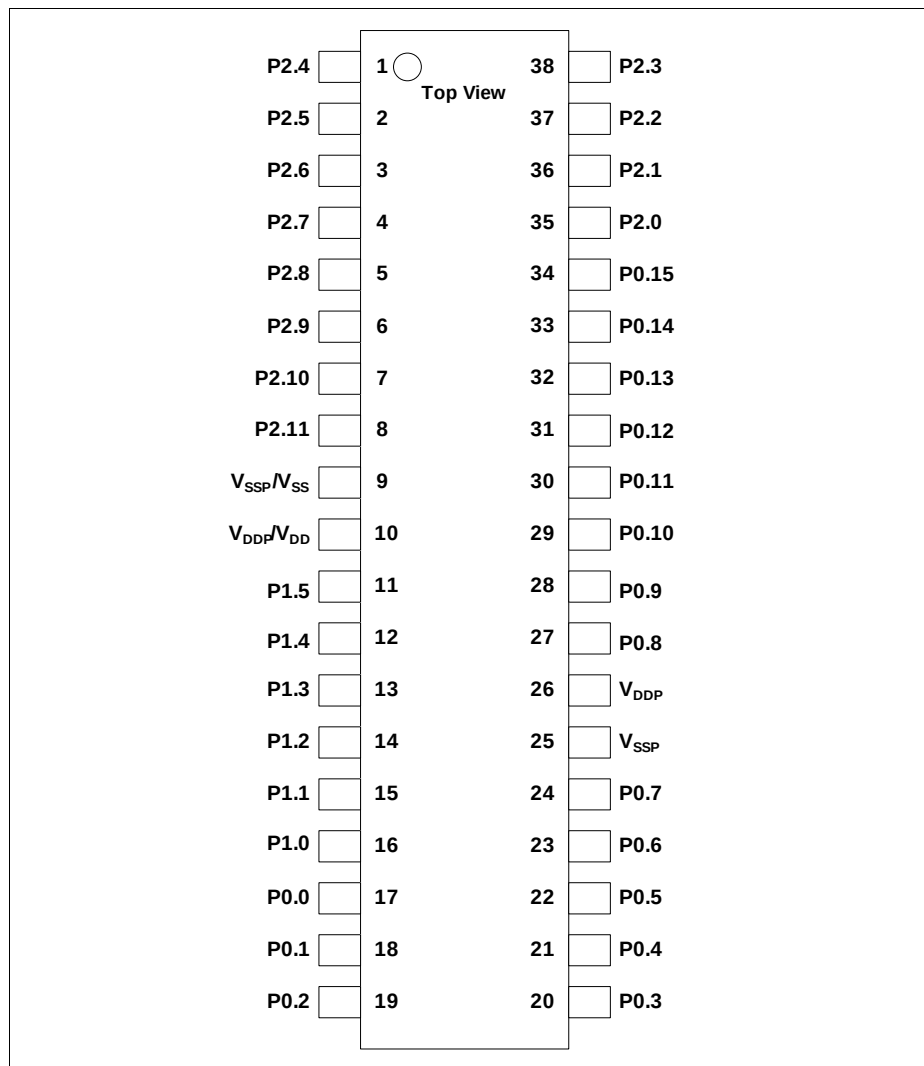


Figure 4 XMC1300 PG-TSSOP-38 Pin Configuration (top view)

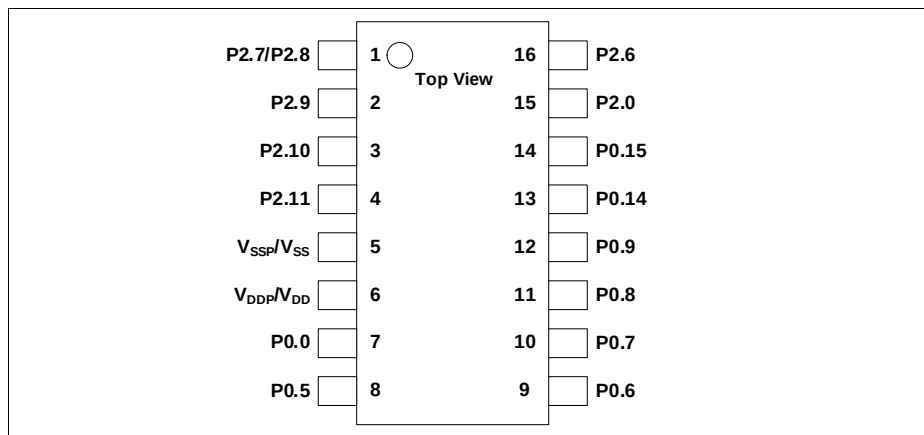


Figure 5 XMC1300 PG-TSSOP-16 Pin Configuration (top view)

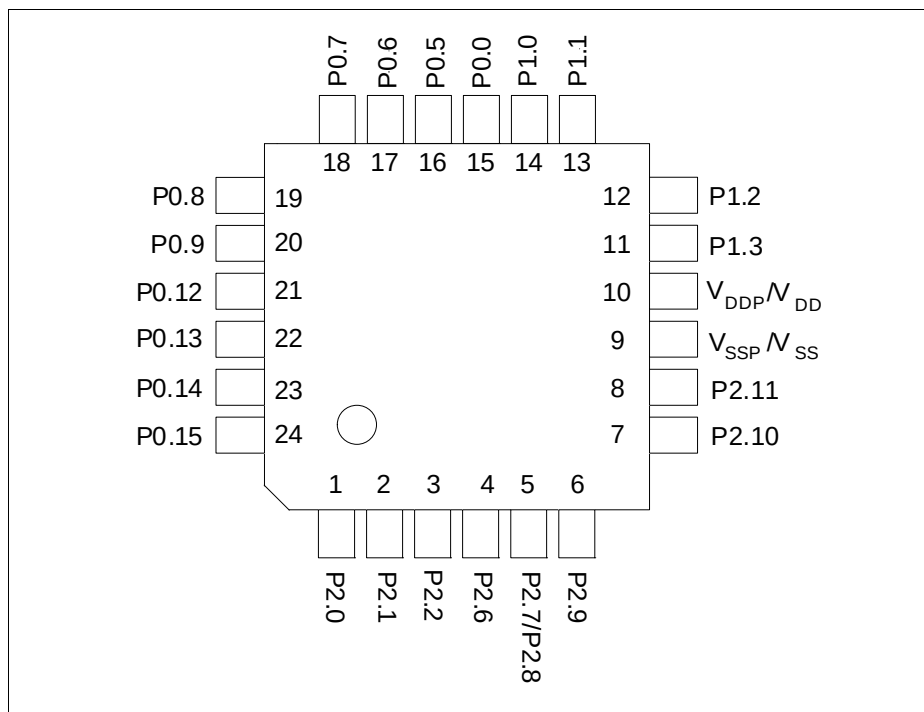


Figure 6 XMC1300 PG-VQFN-24 Pin Configuration (top view)

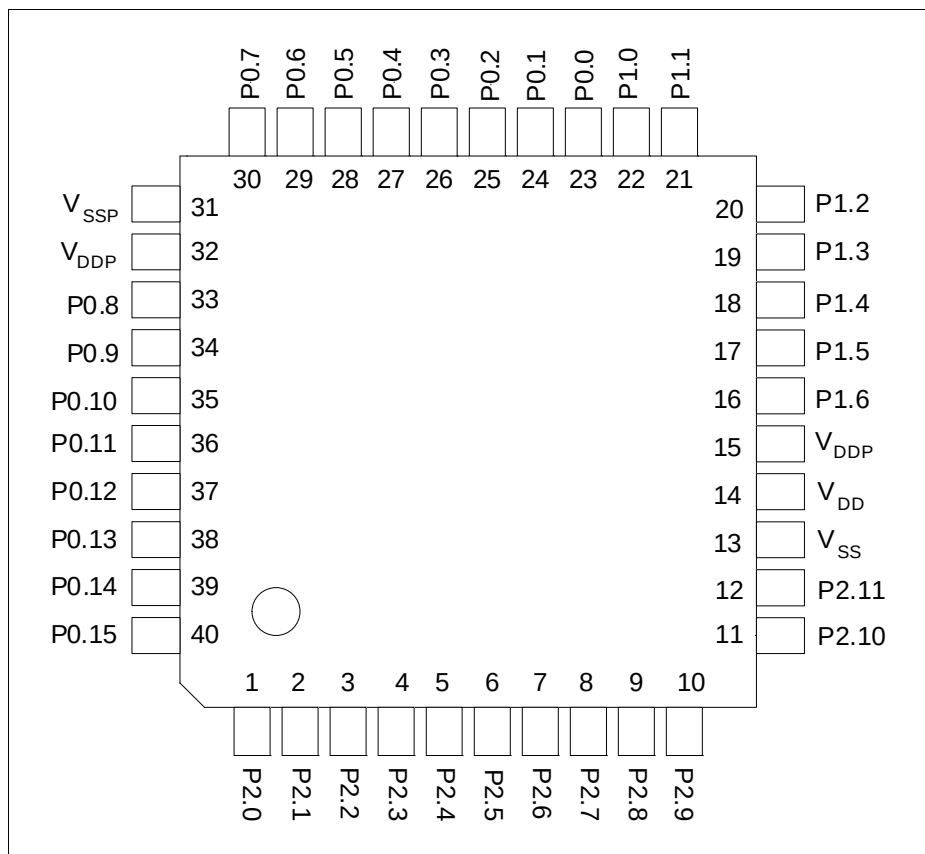


Figure 7 XMC1300 PG-VQFN-40 Pin Configuration (top view)

General Device Information

Table 6 Package Pin Mapping

Function	VQFN 40	TSSOP 38	VQFN 24	TSSOP 16	Pad Type	Notes
VDDP	15	10	10	6	Power	I/O port supply
VSSP	31	25	-	-	Power	I/O port ground
VDDP	32	26	-	-	Power	I/O port supply
VSSP	Exp. Pad	-	Exp. Pad	-	Power	Exposed Die Pad The exposed die pad is connected internally to VSSP. For proper operation, it is mandatory to connect the exposed pad to the board ground. For thermal aspects, please refer to the Package and Reliability chapter.

3 Electrical Parameter

This section provides the electrical parameter which are implementation-specific for the XMC1300.

3.1 General Parameters

3.1.1 Parameter Interpretation

The parameters listed in this section represent partly the characteristics of the XMC1300 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are indicated by the abbreviations in the "Symbol" column:

- **CC**
Such parameters indicate **C**ontroller **C**haracteristics, which are distinctive feature of the XMC1300 and must be regarded for a system design.
- **SR**
Such parameters indicate **S**ystem **R**equirements, which must be provided by the application system in which the XMC1300 is designed in.

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 9 Absolute Maximum Rating Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_S	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on any pin with respect to V_{SSP}	V_{IN}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	whichever is lower
Voltage on any analog input pin with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	–
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute sum of all input currents during overload condition	$\Sigma I_{IN} $	SR	–	–	50	mA	–
Analog comparator input voltage	V_{CM}	SR	-0.3	–	$V_{DDP} + 0.3$	V	

3.2.3 Out of Range Comparator (ORC) Characteristics

The Out-of-Range Comparator (ORC) triggers on analog input voltages (V_{AIN}) above the V_{DDP} on selected input pins (ORCx.AIN) and generates a service request trigger (ORCx.OUT).

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 13 Out of Range Comparator (ORC) Characteristics (Operating Conditions apply; $V_{DDP} = 3.0\text{ V} - 5.5\text{ V}$; $C_L = 0.25\text{ pF}$)

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
DC Switching Level	V_{ODC}	CC	60	–	120	mV	$V_{AIN} \geq V_{DDP} + V_{ODC}$
Hysteresis	V_{OHYS}	CC	25	–	V_{ODC}	mV	
Always detected Overvoltage Pulse	t_{OPDD}	CC	103	–	–	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			88	–	–	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Never detected Overvoltage Pulse	t_{OPDN}	CC	–	–	21	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			–	–	11	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Detection Delay	t_{ODD}	CC	39	–	132	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			31	–	121	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Release Delay	t_{ORD}	CC	44	–	240	ns	$V_{AIN} \leq V_{DDP}$; $V_{DDP} = 5\text{ V}$
			57	–	340	ns	$V_{AIN} \leq V_{DDP}$; $V_{DDP} = 3.3\text{ V}$
Enable Delay	t_{OED}	CC	–	–	300	ns	ORCCTRL.ENORCx = 1

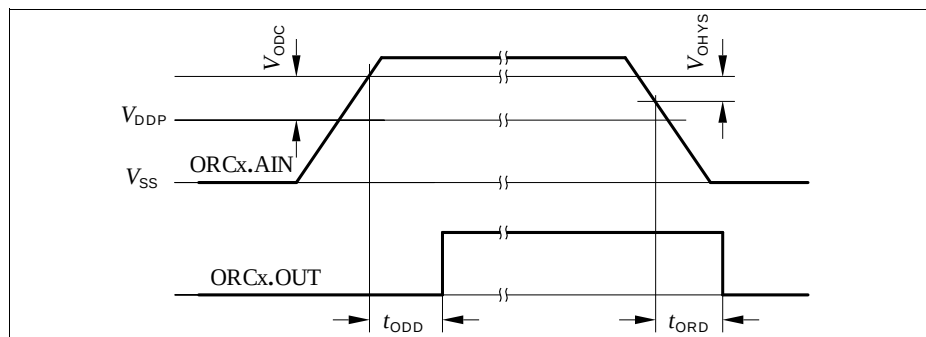


Figure 9 ORCx.OUT Trigger Generation

3.2.7 Flash Memory Parameters

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 18 Flash Memory Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Erase Time per page	t_{ERASE} CC	6.8	7.1	7.6	ms	
Program time per block	$t_{\text{PSE}}^{\text{CC}}$	102	152	204	μs	
Wake-Up time	t_{WU} CC	–	32.2	–	μs	
Read time per word	t_{a} CC	–	50	–	ns	
Data Retention Time	t_{RET} CC	10	–	–	years	Max. 100 erase / program cycles
Flash Wait States ¹⁾	N_{WSFLASH} CC	0	0.5	–		$f_{\text{MCLK}} = 8 \text{ MHz}$
		0	1.4	–		$f_{\text{MCLK}} = 16 \text{ MHz}$
		1	1.9	–		$f_{\text{MCLK}} = 32 \text{ MHz}$
Erase Cycles per page	N_{ECYC} CC	–	–	$5 \cdot 10^4$	cycles	
Total Erase Cycles	N_{TECYC} CC	–	–	$2 \cdot 10^6$	cycles	

1) Flash wait states are automatically inserted by the Flash module during memory read when needed. Typical values are calculated from the execution of the Dhrystone benchmark program.

Electrical Parameter

Figure 14 shows the typical curves for the accuracy of DCO1, with and without calibration based on temperature sensor, respectively.

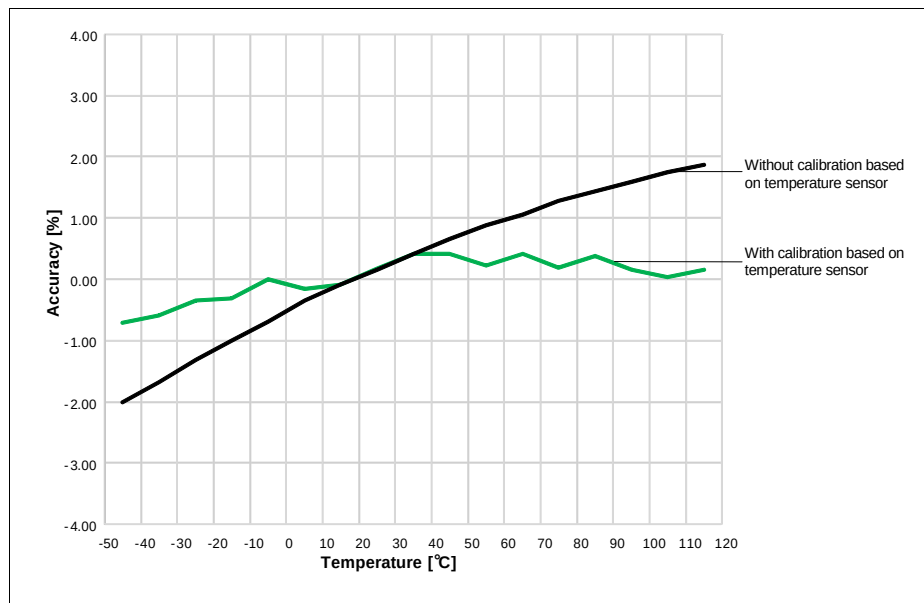


Figure 14 Typical DCO1 accuracy over temperature

Table 22 provides the characteristics of the 32 kHz clock output from digital controlled oscillators, DCO2 in XMC1300.

Table 22 32 kHz DCO2 Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit	Test Conditions
			Min.	Typ.	Max.		
Nominal frequency	f_{NOM}	CC	32.5	32.75	33	kHz	under nominal conditions ¹⁾ after trimming
Accuracy	Δf_{LT}	CC	-1.7	—	3.4	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature (0 °C to 85 °C) ²⁾
			-3.9	—	4.0	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature (-40 °C to 105 °C) ²⁾

1) The deviation is relative to the factory trimmed frequency at nominal V_{DDC} and $T_{\text{A}} = + 25\text{ °C}$.

2) Not subject to production test, verified by design/characterisation.

3.3.5 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 23 SWD Interface Timing Parameters(Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
SWDCLK high time	t_1 SR	50	—	500000	ns	—
SWDCLK low time	t_2 SR	50	—	500000	ns	—
SWDIO input setup to SWDCLK rising edge	t_3 SR	10	—	—	ns	—
SWDIO input hold after SWDCLK rising edge	t_4 SR	10	—	—	ns	—
SWDIO output valid time after SWDCLK rising edge	t_5 CC	—	—	68	ns	$C_L = 50$ pF
		—	—	62	ns	$C_L = 30$ pF
SWDIO output hold time from SWDCLK rising edge	t_6 CC	4	—	—	ns	

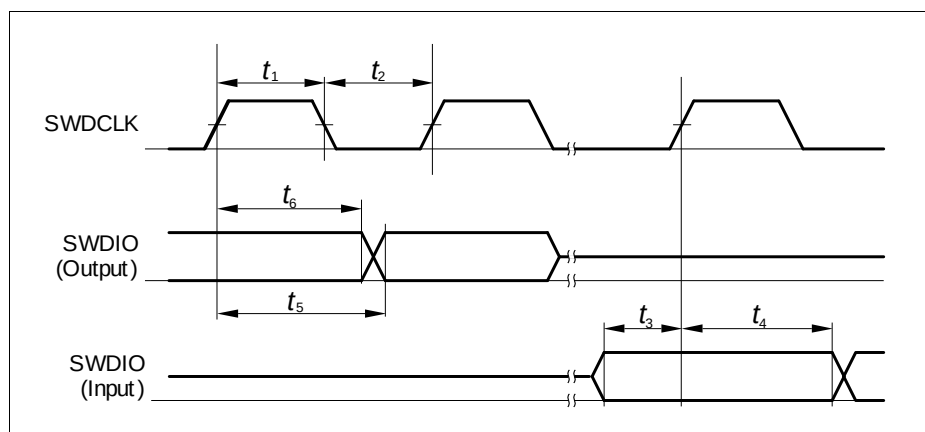


Figure 15 SWD Timing

Table 26 USIC SSC Slave Mode Timing (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Receive data input DX0/DX[5:3] setup time to shift clock receive edge ¹⁾	t_{12} SR	10	–	–	ns	
Data input DX0/DX[5:3] hold time from clock input DX1 receive edge ¹⁾	t_{13} SR	10	–	–	ns	
Data output DOUT[3:0] valid time	t_{14} CC	-	–	80	ns	

1) These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).

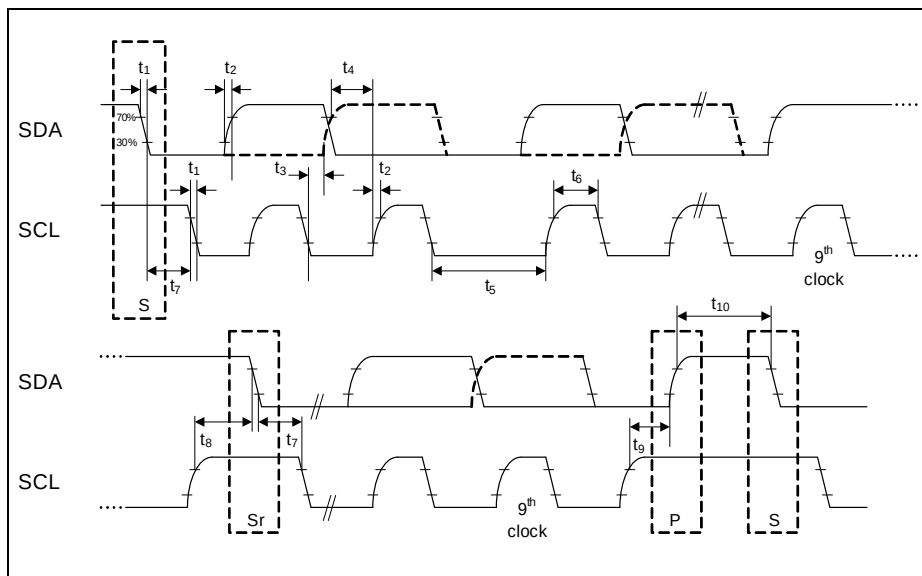


Figure 17 USIC IIC Stand and Fast Mode Timing

3.3.7.3 Inter-IC Sound (IIS) Interface Timing

The following parameters are applicable for a USIC channel operated in IIS mode.

Note: Operating Conditions apply.

Table 29 USIC IIS Master Transmitter Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Clock period	t_1 CC	$2/f_{MCLK}$	-	-	ns	$V_{DDP} \geq 3\text{ V}$
		$4/f_{MCLK}$	-	-	ns	$V_{DDP} < 3\text{ V}$
Clock HIGH	t_2 CC	$0.35 \times t_{1min}$	-	-	ns	
Clock Low	t_3 CC	$0.35 \times t_{1min}$	-	-	ns	
Hold time	t_4 CC	0	-	-	ns	
Clock rise time	t_5 CC	-	-	$0.15 \times t_{1min}$	ns	

The internal power consumption is defined as

$$P_{\text{INT}} = V_{\text{DDP}} \times I_{\text{DDP}} \text{ (switching current and leakage current).}$$

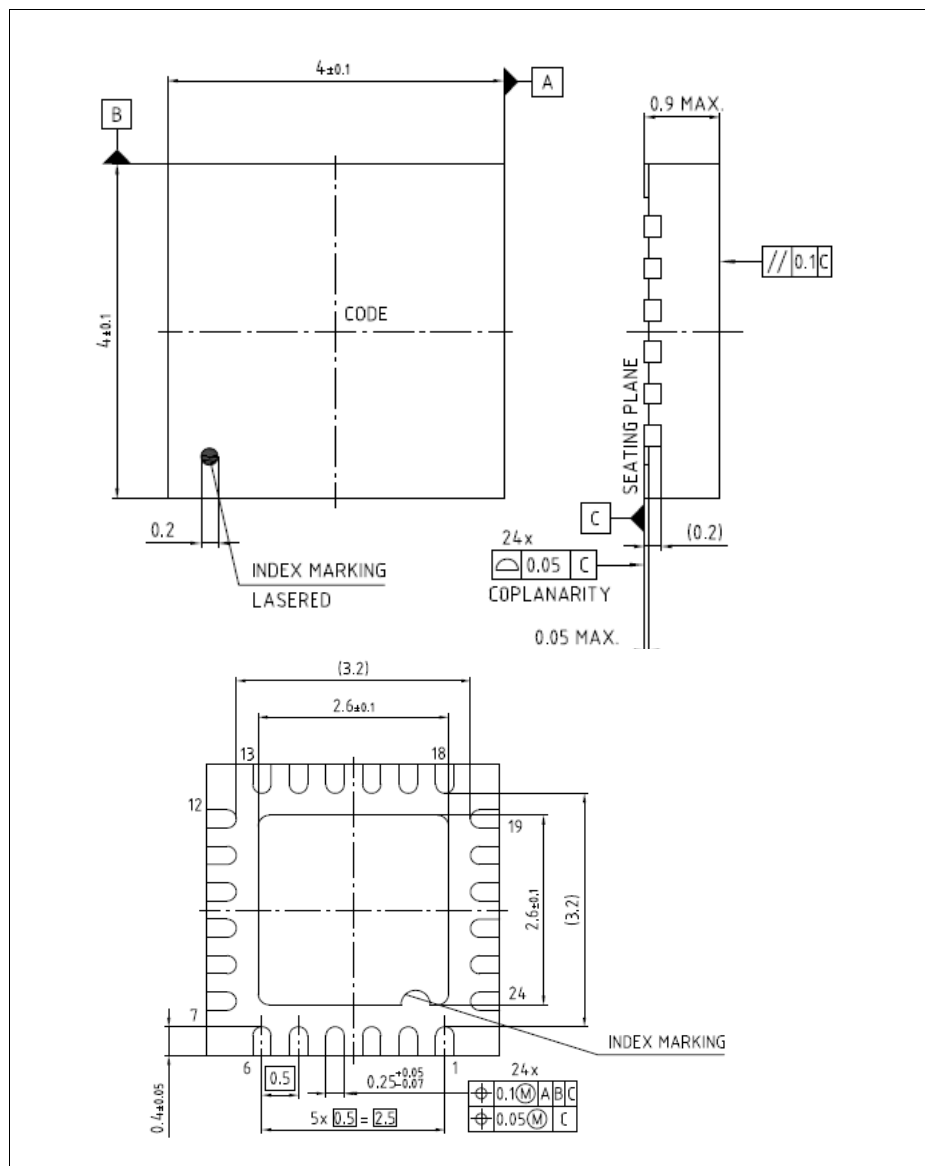
The static external power consumption caused by the output drivers is defined as

$$P_{\text{IOSTAT}} = \Sigma((V_{\text{DDP}} - V_{\text{OH}}) \times I_{\text{OH}}) + \Sigma(V_{\text{OL}} \times I_{\text{OL}})$$

The dynamic external power consumption caused by the output drivers (P_{IODYN}) depends on the capacitive load connected to the respective pins and their switching frequencies.

If the total power dissipation for a given system configuration exceeds the defined limit, countermeasures must be taken to ensure proper system operation:

- Reduce V_{DDP} , if possible in the system
- Reduce the system frequency
- Reduce the number of output pins
- Reduce the load on active output drivers



5 Quality Declaration

Table 32 shows the characteristics of the quality parameters in the XMC1300.

Table 32 Quality Parameters

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
ESD susceptibility according to Human Body Model (HBM)	V_{HBM} SR	-	2000	V	Conforming to EIA/JESD22-A114-B
ESD susceptibility according to Charged Device Model (CDM) pins	V_{CDM} SR	-	500	V	Conforming to JESD22-C101-C
Moisture sensitivity level	MSL CC	-	3	-	JEDEC J-STD-020C

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